

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10760300	CHEN ET AL.
Examiner	Art Unit	
SHANTELL HEIBER	2617	

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
See updated EAST search report	10/17/08	SLH

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
	See EAST search report	10/17/08	SLH

--	--